

INFORMATION AND RECOMMENDED
PROCEDURES FOR APPLICATION
OF THE NO.1 CROSSBAR DIRECT
ACCESS TO NO.101 ESS FEATURE (DADID)

CONTENTS

- | | |
|----------------------------------------------|---------------------------------|
| 1. CIRCUIT AND TEST INFORMATION SUMMARY | 3. PRELIMINARY WORK OPERATIONS |
| 2. CIRCUIT FUNCTION AND MODIFICATION SUMMARY | 4. TESTING OF THE DADID FEATURE |

-
- | | | |
|----------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|-------|--------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|
| 1. <u>CIRCUIT AND TEST INFORMATION SUMMARY</u> | 4.121 | When this condition occurs for a new circuit, it may be blocked normal and all testing deferred until it can be tested in accordance with its associated test method. |
| 1.1 Refer to Table A for a list of the new and modified circuits for DADID operation and their associated test sections. | | |
| 2. <u>CIRCUIT FUNCTION AND MODIFICATION SUMMARY</u> | 4.122 | When this condition occurs for a modified circuit, tests of affected functions should be completed prior to returning the circuit to service. Refer to Table C for a list of these tests. |
| 2.1 Refer to Table B for a description of the new circuit function and existing circuit modification for DADID operation. | | |
| 3. <u>PRELIMINARY WORK OPERATIONS</u> | | <u>NOTE:</u> When job conditions warrant, tests in addition to those of Table C should be performed. These tests may be taken from the associated test method as required. |
| 3.1 The below listed functions may be initiated as job conditions dictate. No particular sequence of functions is required. | | |
| 3.11 Install and wire new and modified equipment as available. See Table A for a list of this equipment. | 4.13 | The below listed sequence of testing is suggested. |
| 3.12 Cable entire job. | (1) | Lead Tests |
| 4. <u>TESTING OF THE DADID FEATURE</u> | (2) | Marker and Sender Link Multiple tests |
| 4.1 <u>Preliminary Testing</u> | (3) | Preference Control and Connector tests |
| 4.11 When the installation and wiring of new and modified equipment is completed, it will, at that time, be listed in accordance with its associated test method as shown in Table A. | (4) | Cross-Connections tests |
| 4.12 In some cases, testing of a new or modified circuit for the DADID feature, at the time it is completed, will not be possible since an associated circuit which also requires installation effort will not yet be completed. | (5) | Operational tests |
| | 4.14 | Refer to Tables A and C to determine a test sequence applicable to your job. |
| | 4.2 | <u>Final Testing</u> |
| | 4.21 | After all installation work and all possible preliminary testing has been completed, the applicable operational tests using the Terminating Sender Test Frame, Terminating Trouble Indicator, and DID Test Frame are required. |

ATTACHMENT

Table A, Page 2 - Table B, Pages 3 & 4
Table C, Page 5

Manager, Crossbar Product Engineering
Control Center

TABLE A
DADID CIRCUIT AND TEST INFORMATION SUMMARY

CIRCUIT TITLE	SD NO.	HANDBOOK	SECTION
TERM. SDR. FS	25013-01	62	222
TERM SDR. LINK	25028-01	62	212
TERM MKR. CONN.	25036-01	62	224
FUSE & TIME ALARM MISC. AUX. ALARM	25046-01 25047-01	Tested with Associated Circuits	
TERM. MKR. MISC	25055-01	62	225
TTI MISC.	25064-01	62	226
TERM. SDR. TST.	25159-01	62	221
NG CONN.	25276-01	62	242
TERM MKR.	25283-01	62	225
TTI	25284-01	62	226
TERM. SDR. DP	25434-01	62	227
TERM. SDR. MF	25455-01	62	228
INC LINK	25457-01	62	211
TERM. SDR. LINK	25459-01	62	212
TERM. MKR. APPL.	27765-01	62	225
DID TST	27766-01	62	235
TERM. MKR. APPL. MISC.	27819-01	62	225
PREF. CONT.	27821-01	62	236
DAP. CONN.	27822-01	62	236
DID. TST. MISC.	27837-01	62	235
ESS. LINE CKT.	1H077-01	62	237
DAP	1H081-01	62	237

TABLE B

DADID CIRCUIT FUNCTION AND MODIFICATION SUMMARY

CIRCUIT TITLE	SD NO.	MODIFICATION
INC. LINK	25457-01	Modified to show connection to the DID Test Circuit.
TERM. SDR. LINK	25028-01	Modification consists of wiring, to add NS0 & NS1 leads to Full Select Terminating Senders. Lead NS0 grounded is a NON DID call. Lead NS1 grounded is a DID, dedicated trunk group call.
TERM. SDR. LINK	25459-01	Wiring to provide means for informing the sender that the call is a DID call from a Dedicated Panel Trunk Group. Lead NS0 grounded is a Non-DID call. Lead NS1 grounded is a call from a dedicated DID trunk group.
TERM SDR., FS	25013-01	Modified to provide equipment to generate a DID number series to the Terminating Marker via the TMC on a 2/4 leads grounded basis. The OB and OG Selections are normally used to select DID number series. However, if the trunk is from a panel office, office frame, the trunks must be dedicated which necessitates the NS0 and NS1 leads from the Terminating Sender Link.
TERM. SDR., DP	25434-01	Modification consists of addition of two small terminal strips and associated wiring. It is made to provide for generation of a DID number series, using the C vertical selections and cross-connecting, to the TM on a 2/4 leads grounded basis.
TERM. SDR., MF	25455-01	Change involves the addition of five relays, one terminal strip, and associated wiring to generate a number series to the TM on a 2/4 lead grounded basis.
TERM. MKR. CONN.	25036-01	Modified to add wiring and/or apparatus for NS- leads from TMA and Senders. Modification consists of wiring only when applied to connectors per Issue 25D or later. When applied to conn. prior to Issue 25, one relay and one 185A network are also required.
TERM MKR.	25283-01	The TM is modified to work with the TMA. The bulk of the modification consists of the registration relays of the TM being replaced by relays in the TMA. Wiring between these circuits provide the TMA with the capability of controlling the TM on DADID type calls.
TERM. MKR. MISC.	25055-01	To show connection to the Miscellaneous Ckt. for the TMA.

TABLE B (CONT'D)

CIRCUIT TITLE	SD NO.	MODIFICATION
PREF. CONT	27821-01	(New) The preference control and associated make busy circuit are used by the TMA to obtain access to Direct Access Pretranslator Connectors. The control circuit functions to permit only one TMA to have access to a particular DAPC at one time.
DAP CONN.	27822-01	(New) The purpose of the DAPC is to connect a TMA to the "on line" DAP.
DAP Same as used in #5 X-BAR	1H081-01	Serves as an interface between the No. 1 Crossbar Terminating Marker and the 101 ESS Program Control.
ESS LINE CKT. Same as used in #5 X-BAR	1H077-01	Serves as an interface between the No. 1 X-BAR Line Link and the 101 ESS Switch Unit.
NG CONN.	25276-01	A Diode Matrix consisting of 80 diodes is added to isolate the ESSHG punchings from other HG punchings in the NG.
FUSE & TIME ALARM	25046-01	To show connection to DID equipment, DID Tst. Ckt. Pretranslator, etc.
MISC. AUX. ALM.	25047-01	To show connection to the DAPC and to No. 101 ESS Maintenance Center Circuit and Power Distance Fuse Alarm Ckt.
NO. TEST CONN.	25251-01	To show connection to the DID Test Circuit.
TERM. SDR. TEST	25159-01	Modification provided for testing DP and MF Term. Sdrs. for DID operation and F.S. Term. Sdrs. for DID operation using OB and OG selections or Dedicated Trunk Group indications to generate DID number series. Consists of addition of 14 relays, 10 keys and 3 lamps and replacement of 2 relays.
TTI	25284-01	Modification consists of addition of 4 relays and 7 lamps plus the major portion of equipment previously provided for LLP operation (154 lamps, 80 relays, 4 jacks).
TTI MISC.	25064-01	Adds lamps DAP- for Direct Access Pretranslators.
DID TEST	27766-01	(New) Provides features to direct calls to any line circuit to effect operational, transmission, voltmeter and no-test access test calls. The test circuit is also arranged to direct test calls to any DAP for the purpose of locating trouble due to faulty transmission exchanges between the Terminating Marker and the DAP.

TABLE C

DADID AFFECTED FUNCTION TEST SUMMARY

CIRCUIT TITLE	SD NO.	HANDBOOK	SECTION	TEST
TERM. SDR. FS	25013-01	62	222	PARAGRAPH 9, TABLE C, NOTE 1
TERM. DDR. LINK	25028-01	62	212	PARAGRAPH 7
TERM MKR. CONN.	25036-01	62	224	PARAGRAPH 16
FUSE & TIME ALARM MISC. AUX. ALARM	25046-01 25047-01	Tested with Associated Circuit		
TERM. MKR. MISC.	25055-01	62	225	**
TTI MISC.	25064-01	62	226	**
TERM. SDR. TST.	25159-01	62	221	*
NG CONN	25276-01	62	242	PARAGRAPH 8
TERM. MKR.	25283-01	62	225	**
TTI	25284-01	62	226	**
TERM. SDR. DP	25434-01	62	227	PARAGRAPH 8, TABLE C, NOTE 2
TERM. SDR. MF	25455-01	62	228	PARAGRAPH 9, TABLE B, NOTE 1
INC LINK	25457-01	62	211	NOT REQUIRED
TERM SDR. LINK	25459-01	62	212	PARAGRAPH 7
TERM MKR. APPL.	27765-01	62	225	**
TERM MKR. APPL. MISC.	27819-01	62	225	**

* The Terminating Sender Test Frame is tested when the tests shown for Handbook 62, Sections 222, 227, and 228 are performed.

** When the Terminating Marker and Terminating Marker Applique and/or TTI are furnished new, all tests of Handbook 62, Sections 225 and 226 should be completed before placing this equipment in service.

When the Terminating Marker and/or TTI are modified, the below listed tests of Handbook 62 should be completed before returning this equipment to service:

<u>SECTION</u>	<u>PARAGRAPH(S)</u>
225	6
225.1	2 and 6
225.2	9.1
225.3	39.5
225.4	1 through 6.1
225.7	7 and 8